

Notice of References Cited		Application/Control No. 10/664,000	Applicant(s)/Patent Under Reexamination MIR, KALIM	
		Examiner FRANK W. LU	Art Unit 1634	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,268,146 B1	07-2001	Shultz et al.	435/6
*	B US-5,256,536	10-1993	Miyada et al.	435/6
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	The definition for scanning probe microscopy from Wikipedia, the free encyclopedia. Printed on August 3, 2008.
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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